Application/Control No.	Applicant(s)/Patent under Reexamination	
10/567,327	ISHIKAWA ET AL.	
Examiner	Art Unit	_
Khanh T. Nguyen	1751	

	SEAR	CHED	
Class	Subclass	Date	Examiner
510	522	12/20/2006	K.N
8	115.51	12/20/2006	K.N
510	130	12/20/2006	K.N
510	516	12/20/2006	K.N
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
All searches were done on EAST.	12/20/2006	K.N		
Inventor name search was done on PALM.	12/20/2006	K.N		
Consulted with Mr. Mark Kopec (A.U. 1751)	12/20/2006	K.N		
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